

Sheet 1 of 1

U.S. Department of Commerce
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Inf rmati n Disclosur Stat ment
by Applicant
(Use several sheets if necessary)
(37 CFR §1.98(b))

Attorney's Docket No.
13292-003001

Application No.
10/032,876

Applicant
Kamel Ayadi

Filing Date
October 24, 2001

Group Art Unit

U.S. Patent Documents							
Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5,861,882	01/19/99	Sprenger et al.			
	AB	5,349,539	09/20/94	Moriyasu			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

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Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation Yes No
	AL						
	AM						
	AN						
	AO						
	AP						

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
US	AQ	Michejda, J. and Kim, S. K., "A Precision CMOS Bandgap Reference", <u>IEEE Journal of Solid-State Circuits</u> , Vol. SC-19, No. 6, 1014-1021, 1984.
US	AR	Sylvester et al., "Investigation of Interconnect Capacitance Characterization Using Charge-Based Capacitance Measurement (CBCM) Technique and Three-Dimensional Simulation", <u>IEEE Journal of Solid-State Circuits</u> , Vol. 33, No. 3, 449-453, 1998.
	AS	
	AT	

Examiner Signature

AMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with communication to applicant.

Date Considered
6/16/03

Substitute Disclosure Form (PTO-1449)